



FDB33N25

250V N-Channel MOSFET

Features

- 33A, 250V, $R_{DS(on)} = 0.094\Omega$ @ $V_{GS} = 10$ V
- Low gate charge (typical 36.8 nC)
- Low C_{rss} (typical 39 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

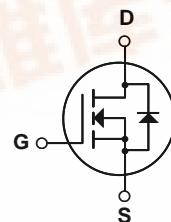
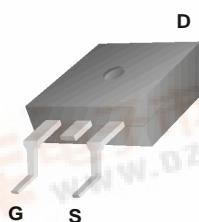
September 2005

UniFET™

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



Absolute Maximum Ratings

Symbol	Parameter	FDB33N25	Unit
V_{DSS}	Drain-Source Voltage	250	V
I_D	Drain Current - Continuous ($T_C = 25^\circ C$) - Continuous ($T_C = 100^\circ C$)	33 20.4	A A
I_{DM}	Drain Current - Pulsed	(Note 1)	A
V_{GSS}	Gate-Source voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	mJ
I_{AR}	Avalanche Current	(Note 1)	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	V/ns
P_D	Power Dissipation ($T_C = 25^\circ C$) - Derate above $25^\circ C$	235 1.89	W W/ $^\circ C$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ C$
T_L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ C$

Thermal Characteristics

Symbol	Parameter	Min.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	0.53	$^\circ C/W$
$R_{\theta JA}^*$	Thermal Resistance, Junction-to-Ambient*	--	40	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	$^\circ C/W$

* When mounted on the minimum pad size recommended (PCB Mount)

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB33N25	FDB33N25TM	D2-PAK	330mm	24mm	800

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Conditions	Min.	Typ.	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0\text{V}$, $I_D = 250\mu\text{A}$	250	--	--	V
$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, Referenced to 25°C	--	0.25	--	$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 250\text{V}$, $V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 200\text{V}$, $T_C = 125^\circ\text{C}$	--	--	1 10	μA μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30\text{V}$, $V_{\text{DS}} = 0\text{V}$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30\text{V}$, $V_{\text{DS}} = 0\text{V}$	--	--	-100	nA
On Characteristics						
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250\mu\text{A}$	3.0	--	5.0	V
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10\text{V}$, $I_D = 16.5\text{A}$	--	0.077	0.094	Ω
g_{FS}	Forward Transconductance	$V_{\text{DS}} = 40\text{V}$, $I_D = 16.5\text{A}$	(Note 4)	--	26.6	--
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{\text{DS}} = 25\text{V}$, $V_{\text{GS}} = 0\text{V}$, $f = 1.0\text{MHz}$	--	1640	2135	pF
C_{oss}	Output Capacitance		--	330	430	pF
C_{rss}	Reverse Transfer Capacitance		--	39	59	pF
Switching Characteristics						
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 125\text{V}$, $I_D = 33\text{A}$ $R_G = 25\Omega$	--	35	80	ns
t_r	Turn-On Rise Time		--	230	470	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	75	160	ns
t_f	Turn-Off Fall Time		(Note 4, 5)	--	120	250
Q_g	Total Gate Charge	$V_{\text{DS}} = 200\text{V}$, $I_D = 33\text{A}$ $V_{\text{GS}} = 10\text{V}$	--	36.8	48	nC
Q_{gs}	Gate-Source Charge		--	10	--	nC
Q_{gd}	Gate-Drain Charge		(Note 4, 5)	--	17	--
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current		--	--	33	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	132	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0\text{V}$, $I_S = 33\text{A}$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$V_{\text{GS}} = 0\text{V}$, $I_S = 33\text{A}$	--	220	--	ns
Q_{rr}	Reverse Recovery Charge	$dI_F/dt = 100\text{A}/\mu\text{s}$	(Note 4)	--	1.71	--
NOTES:						
1. Repetitive Rating: Pulse width limited by maximum junction temperature						
2. $L = 1.35\text{mH}$, $I_{\text{AS}} = 33\text{A}$, $V_{\text{DD}} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$						
3. $I_{\text{SD}} \leq 33\text{A}$, $dI/dt \leq 200\text{A}/\mu\text{s}$, $V_{\text{DD}} \leq \text{BV}_{\text{DSS}}$, Starting $T_J = 25^\circ\text{C}$						
4. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$						
5. Essentially Independent of Operating Temperature Typical Characteristics						

Typical Performance Characteristics

Figure 1. On-Region Characteristics

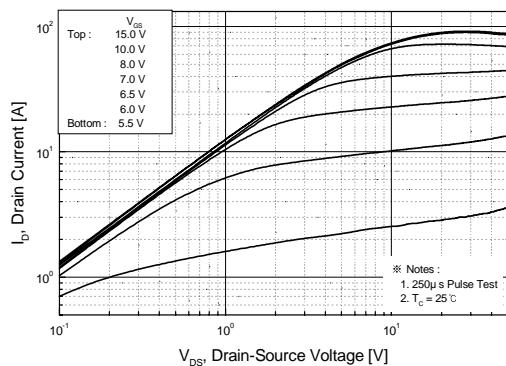


Figure 2. Transfer Characteristics

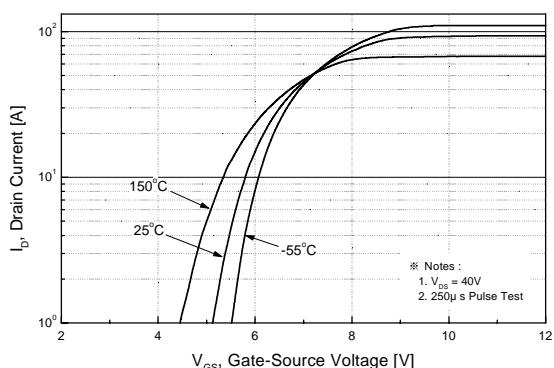


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

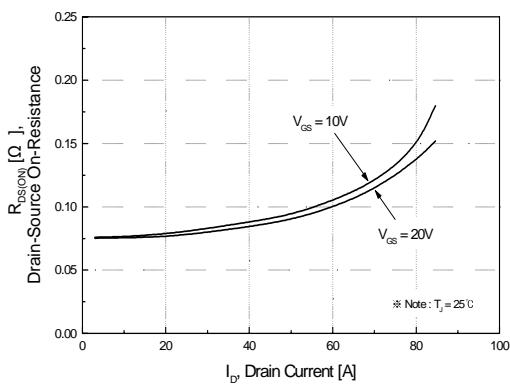


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

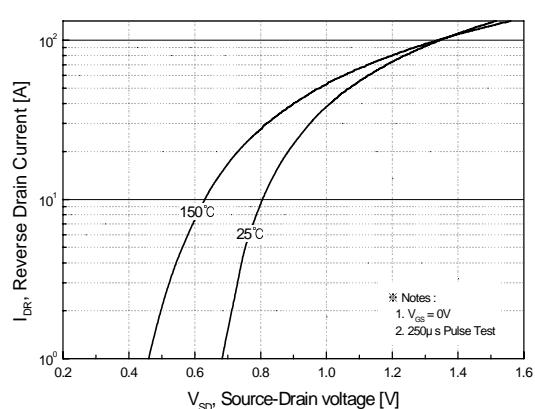


Figure 5. Capacitance Characteristics

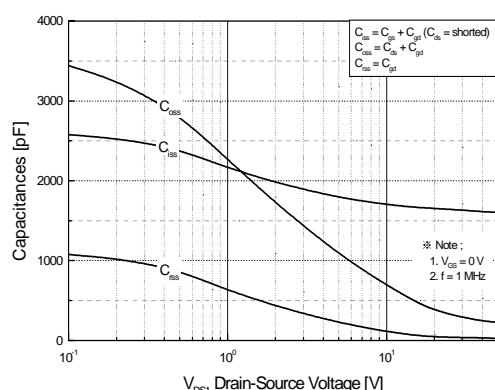
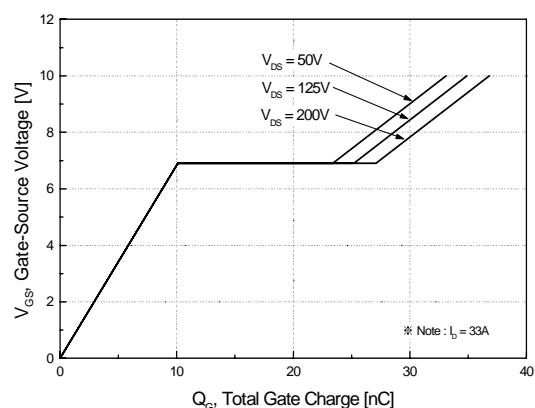


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

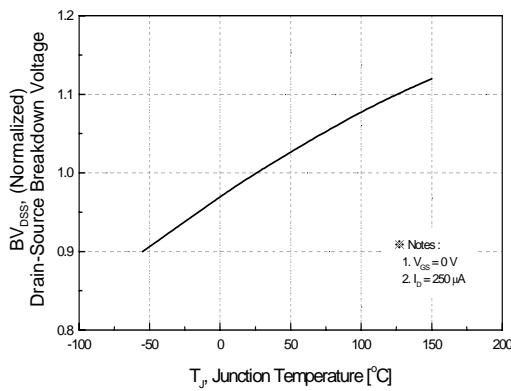


Figure 8. On-Resistance Variation vs. Temperature

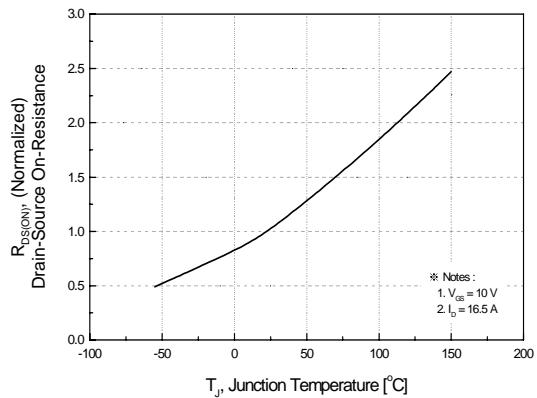


Figure 9. Maximum Safe Operating Area

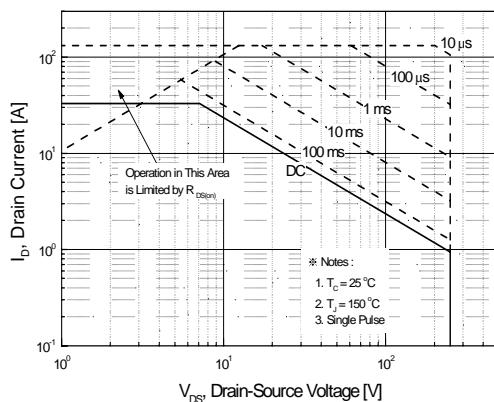


Figure 10. Maximum Drain Current vs. Case Temperature

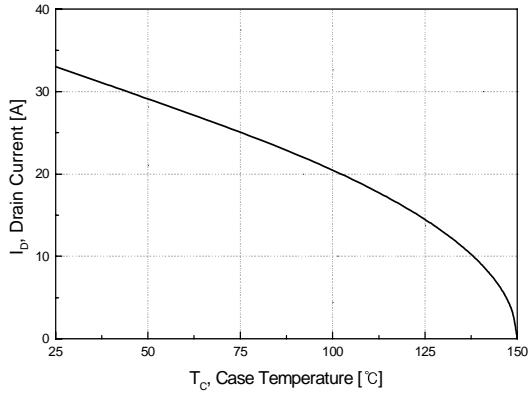
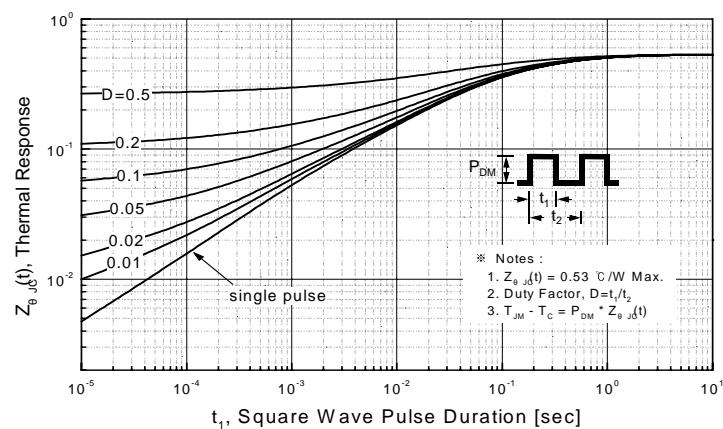
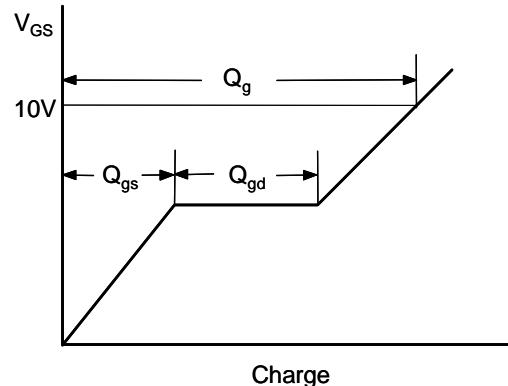
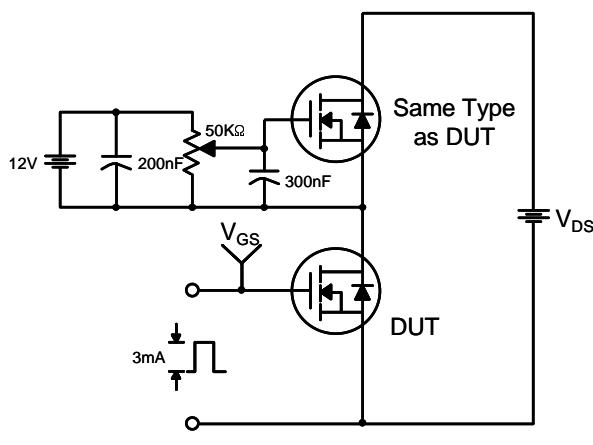


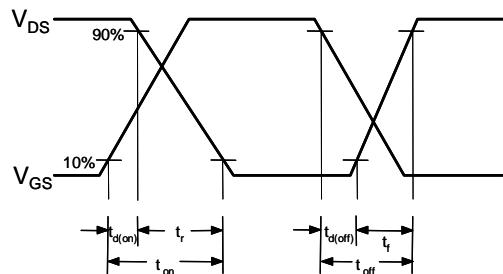
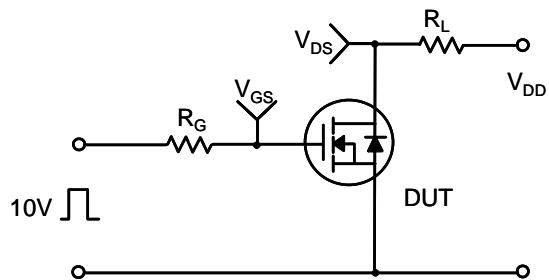
Figure 11. Transient Thermal Response Curve



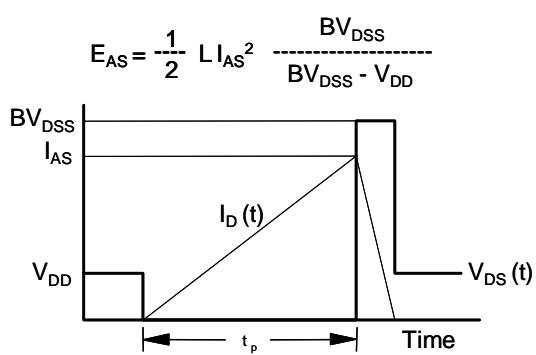
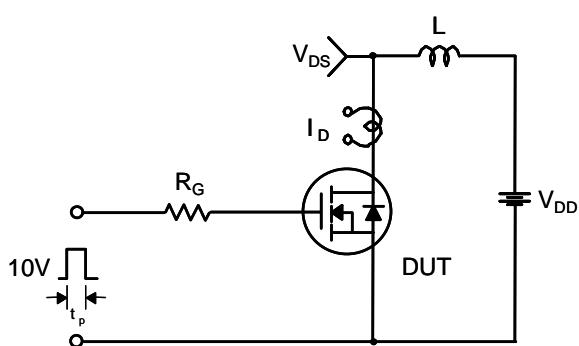
Gate Charge Test Circuit & Waveform



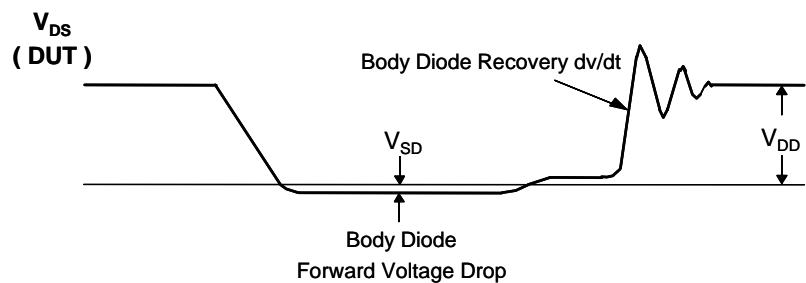
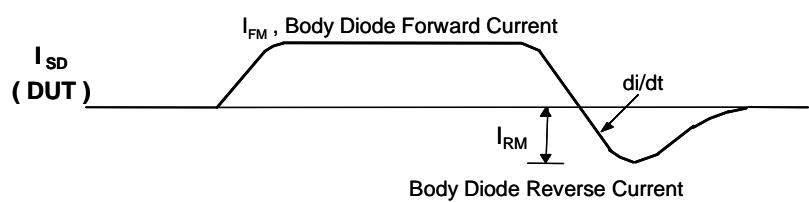
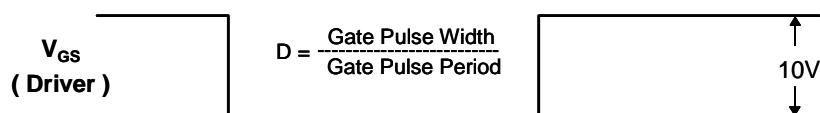
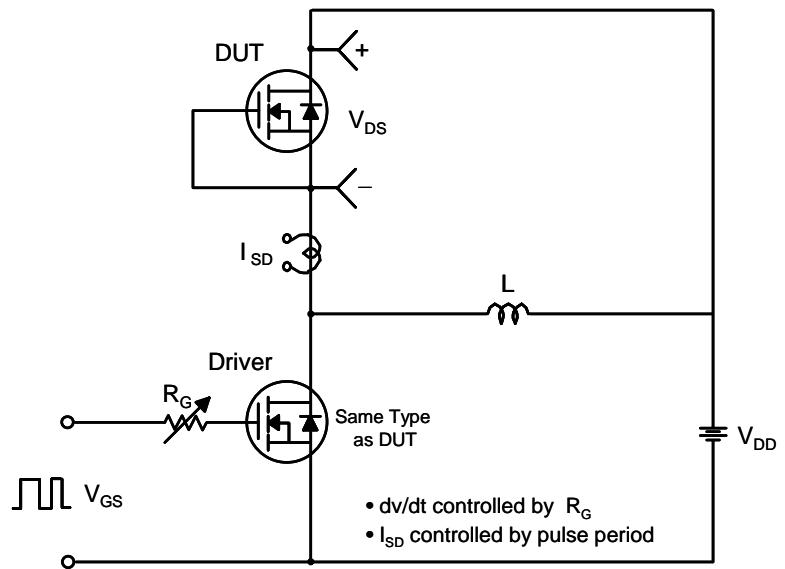
Resistive Switching Test Circuit & Waveforms

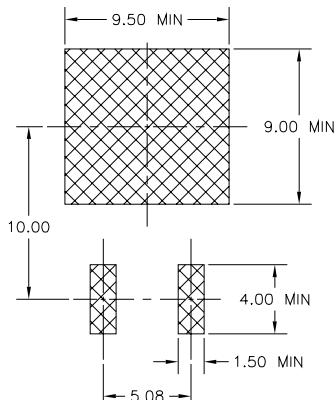
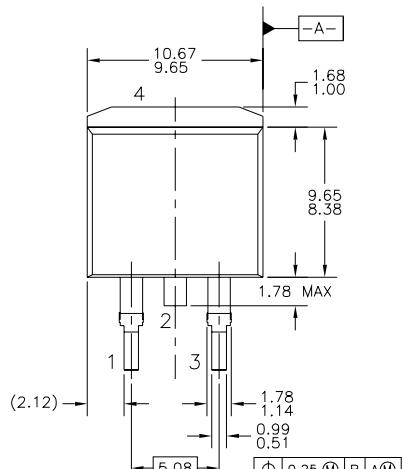


Unclamped Inductive Switching Test Circuit & Waveforms

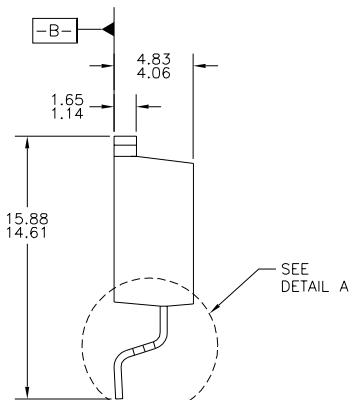
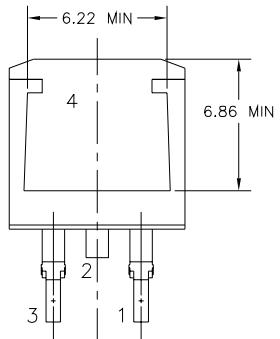


Peak Diode Recovery dv/dt Test Circuit & Waveforms

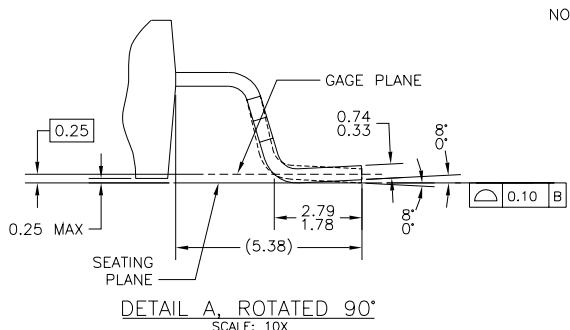


Mechanical Dimensions**D2-PAK**

LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED
 A) ALL DIMENSIONS ARE IN MILLIMETERS.
 B) REFERENCE JEDEC, TO-263, ISSUE D,
 VARIATION AB, DATED JULY 2003.
 C) DIMENSIONING AND TOLERANCING PER
 ANSI Y14.5M - 1982.
 D) LOCATION OF THE PIN HOLE MAY VARY
 (LOWER LEFT CORNER, LOWER CENTER
 AND CENTER OF THE PACKAGE).
 E) PRESENCE OF TRIMMED CENTER LEAD
 IS OPTIONAL.

DETAIL A, ROTATED 90°
SCALE: 10X

T0263A02REV0

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EcoSPARK™	I²C™	MSXPro™	RapidConnect™	UniFET™
E²CMOST™	i-Lo™	OCX™	µSerDes™	VCX™
EnSigna™	ImpliedDisconnect™	OCXPro™	SILENT SWITCHER®	Wire™
FACT™	IntelliMAX™	OPTOLOGIC®	SMART START™	
FACT Quiet Series™		OPTOPLANAR™	SPMT™	
Across the board. Around the world.™		PACMAN™	Stealth™	
The Power Franchise®		POP™	SuperFET™	
Programmable Active Droop™		Power247™	SuperSOT™-3	
		PowerEdge™	SuperSOT™-6	

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